

<b>Notice of References Cited</b>	Application/Control No. 10/625,238	Applicant(s)/Patent Under Reexamination XUE, YALEI	
	Examiner Jean F. Duverne	Art Unit 2839	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-6,312,293 B1	11-2001	Wang, Suiya	439/677
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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